

## Supplementary Information

### Excellent response to near ultraviolet light and large intervalley scatterings of electrons in 2D SnS<sub>2</sub>

Yu Wu,<sup>1</sup> Junbo He,<sup>1</sup> Ying Chen,<sup>2</sup> Mingran Kong,<sup>1</sup> Yiming Zhang,<sup>1</sup>  
Xiaobing Hu,<sup>3</sup> Jianwei Lian,<sup>3</sup> Hao Zhang,<sup>1,4,5,†</sup> and Rongjun Zhang<sup>1,6,4,‡</sup>

<sup>1</sup>*Key Laboratory of Micro and Nano Photonic Structures (MOE)  
and Key Laboratory for Information Science of Electromagnetic  
Waves (MOE) and Department of Optical Science and Engineering,  
Fudan University, Shanghai 200433, China*

<sup>2</sup>*Department of Light Sources and Illuminating Engineering,  
and Academy for Engineering & Technology,  
Fudan University, Shanghai, 200433, China*

<sup>3</sup>*State Key Laboratory of ASIC and System,  
School of Microelectronics, Fudan University, Shanghai 200433, China*

<sup>4</sup>*Yiwu Research Institute of Fudan University,  
Chengbei Road, Yiwu City, Zhejiang 322000, China*

<sup>5</sup>*Nanjing University, National Laboratory of Solid State Microstructure, Nanjing 210093, China*

<sup>6</sup>*Academy for Engineering & Technology,  
Fudan University, Shanghai, 200433, China*

## I. CHARACTERIZATION OF AS-SYNTHESIZED $\text{SnS}_2$ FILMS

A series of  $\text{SnS}_2$  films (S1-S4) were prepared with different thickness. When the sample is thin, good uniformity can be maintained. Fig. S1(a) shows the Atomic force microscopy (AFM) image of sample S1, the surface of the film is relatively smooth, and the root mean square roughness is 0.58 nm. Raman spectra of the investigated  $\text{SnS}_2$  films are presented in Fig. S1(b). X-ray photoelectron spectroscopy (XPS) was used to examine the chemical state of the as-grown  $\text{SnS}_2$  samples shown in Fig. S1(c). X-ray diffraction (XRD) pattern of as-grown samples are shown in Fig. S1(d). Fig. S1(e) shows the height profile of ultrathin  $\text{SnS}_2$  nanosheet along the auxiliary line in inset (corresponding typical AFM image).

## II. BAND STRUCTURE AND PHONON DISPERSION

The electronic bands and phonon dispersion are shown in Fig. S2. The little groups of each high symmetry point and line are presented on the top of each pictures. Corresponding irreducible representations of each phonon mode are indicated as well.

## III. SELECTION RULE FOR ELECTRON-PHONON COUPLINGS

Based on the group theory, the scattering channels for electron-phonon couplings in Brillouin zone are shown in Fig. S3 for both electrons and holes.

---

<sup>†</sup> Electronic address: zhangh@fudan.edu.cn

<sup>‡</sup> Electronic address: rjzhang@fudan.edu.cn

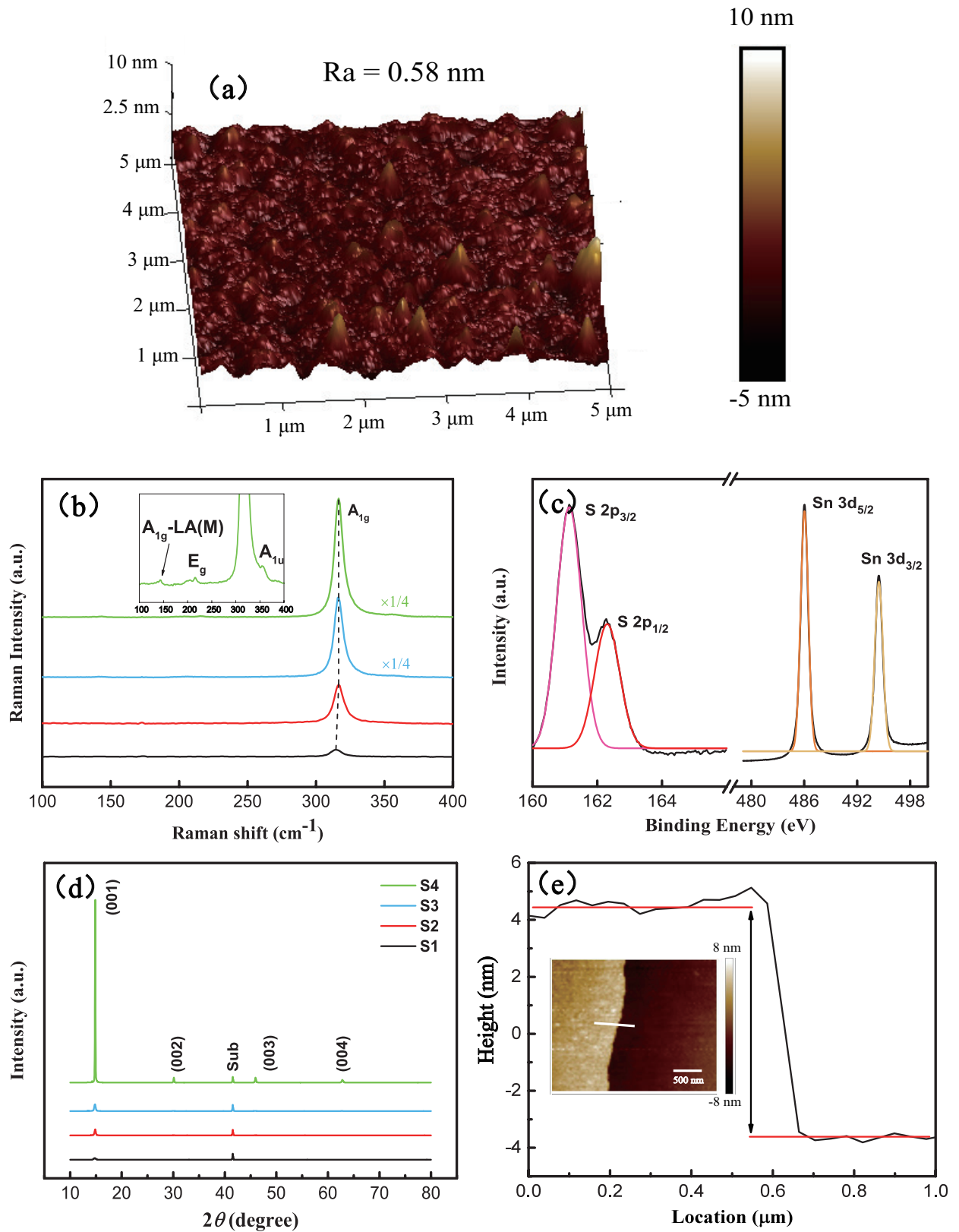


FIG. S1: (a) AFM image of S1 sample (b) Room temperature Raman spectra of SnS<sub>2</sub> films with 532 nm excitation laser. (c) XPS spectrum showing binding states of S 2p and Sn 3d. (d) XRD patterns of the SnS<sub>2</sub> films and sapphire substrates. (e) The height profile of ultrathin SnS<sub>2</sub> corresponding to a typical AFM image.

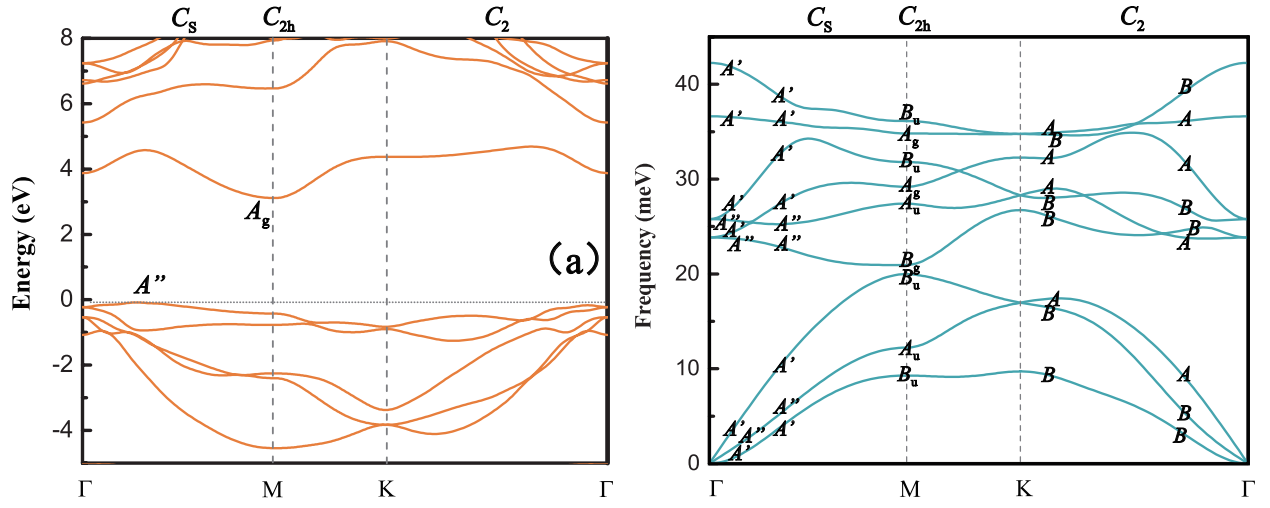


FIG. S2: The electronic band structure and phonon dispersion relation of  $\text{SnS}_2$ .

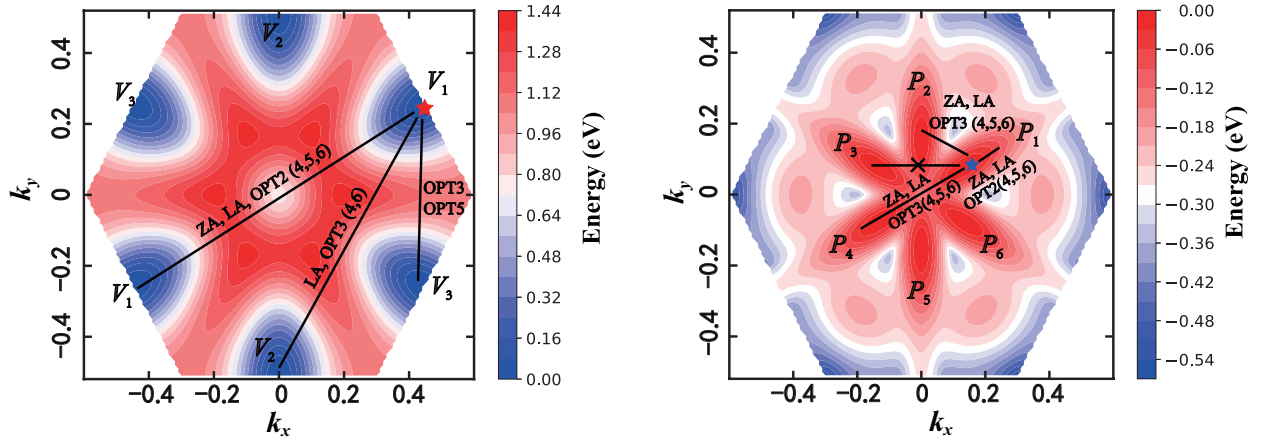


FIG. S3: The transitional K-path of intravalley(peak) and intervalley(peak) scattering for the CBM electrons and VBM holes obtained by group theory.